

## OptiMOS™3 Power-Transistor

### Features

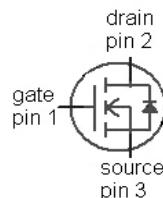
- N-channel, normal level
- Excellent gate charge  $\times R_{DS(on)}$  product (FOM)
- Very low on-resistance  $R_{DS(on)}$
- 175 °C operating temperature
- Pb-free lead plating; RoHS compliant
- Qualified according to JEDEC<sup>1)</sup> for target application
- Ideal for high-frequency switching and synchronous rectification
- Halogen-free according to IEC61249-2-21



### Product Summary

$V_{DS}$	100	V
$R_{DS(on),max}$ TO-263	18	mΩ
$I_D$	43	A

Type	IPP180N10N3 G	IPI180N10N3 G
Package	PG-T0220-3	PG-T0262-3
Marking	180N10N	180N10N



**Maximum ratings**, at  $T_j=25$  °C, unless otherwise specified

Parameter	Symbol	Conditions	Value	Unit
Continuous drain current	$I_D$	$T_C=25$ °C <sup>2)</sup>	43	A
		$T_C=100$ °C	30	
Pulsed drain current <sup>2)</sup>	$I_{D,pulse}$	$T_C=25$ °C	172	
Avalanche energy, single pulse	$E_{AS}$	$I_D=33$ A, $R_{GS}=25$ Ω	50	mJ
Gate source voltage	$V_{GS}$		±20	V
Power dissipation	$P_{tot}$	$T_C=25$ °C	71	W
Operating and storage temperature	$T_j, T_{stg}$		-55 ... 175	°C
IEC climatic category; DIN IEC 68-1			55/175/56	

<sup>1)</sup>J-STD20 and JESD22

<sup>2)</sup> See figure 3

Parameter	Symbol	Conditions	Values			Unit
			min.	typ.	max.	

**Thermal characteristics**

Thermal resistance, junction - case	$R_{thJC}$		-	-	2.1	K/W
Thermal resistance, junction - ambient	$R_{thJA}$	minimal footprint	-	-	62	
		6 cm <sup>2</sup> cooling area <sup>3)</sup>	-	-	40	

**Electrical characteristics**, at  $T_j=25$  °C, unless otherwise specified

**Static characteristics**

Drain-source breakdown voltage	$V_{(BR)DSS}$	$V_{GS}=0$ V, $I_D=1$ mA	100	-	-	V
Gate threshold voltage	$V_{GS(th)}$	$V_{DS}=V_{GS}$ , $I_D=33$ µA	2	2.7	3.5	
Zero gate voltage drain current	$I_{DSS}$	$V_{DS}=100$ V, $V_{GS}=0$ V, $T_j=25$ °C	-	0.1	1	µA
		$V_{DS}=100$ V, $V_{GS}=0$ V, $T_j=125$ °C	-	10	100	
Gate-source leakage current	$I_{GSS}$	$V_{GS}=20$ V, $V_{DS}=0$ V	-	1	100	nA
Drain-source on-state resistance	$R_{DS(on)}$	$V_{GS}=10$ V, $I_D=33$ A	-	15.5	18	mΩ
		$V_{GS}=6$ V, $I_D=16$ A	-	19.3	33	
Gate resistance	$R_G$		-	1.4	-	Ω
Transconductance	$g_{fs}$	$ V_{DS} >2 I_D R_{DS(on)max}$ , $I_D=33$ A	20	40	-	s

<sup>3)</sup> Device on 40 mm x 40 mm x 1.5 mm epoxy PCB FR4 with 6 cm<sup>2</sup> (one layer, 70 µm thick) copper area for drain connection. PCB is vertical in still air.

Parameter	Symbol	Conditions	Values			Unit
			min.	typ.	max.	

**Dynamic characteristics**

Input capacitance	$C_{iss}$	$V_{GS}=0 \text{ V}, V_{DS}=50 \text{ V}, f=1 \text{ MHz}$	-	1350	1800	pF
Output capacitance	$C_{oss}$		-	237	315	
Reverse transfer capacitance	$C_{rss}$		-	11	-	
Turn-on delay time	$t_{d(on)}$	$V_{DD}=50 \text{ V}, V_{GS}=10 \text{ V}, I_D=33 \text{ A}, R_G=1.6 \Omega$	-	12	-	ns
Rise time	$t_r$		-	12	-	
Turn-off delay time	$t_{d(off)}$		-	19	-	
Fall time	$t_f$		-	5	-	

**Gate Charge Characteristics<sup>6)</sup>**

Gate to source charge	$Q_{gs}$	$V_{DD}=50 \text{ V}, I_D=33 \text{ A}, V_{GS}=0 \text{ to } 10 \text{ V}$	-	7	-	nC
Gate to drain charge	$Q_{gd}$		-	4	-	
Switching charge	$Q_{sw}$		-	6	-	
Gate charge total	$Q_g$		-	19	25	
Gate plateau voltage	$V_{plateau}$		-	4.9	-	V
Output charge	$Q_{oss}$	$V_{DD}=50 \text{ V}, V_{GS}=0 \text{ V}$	-	25	33	nC

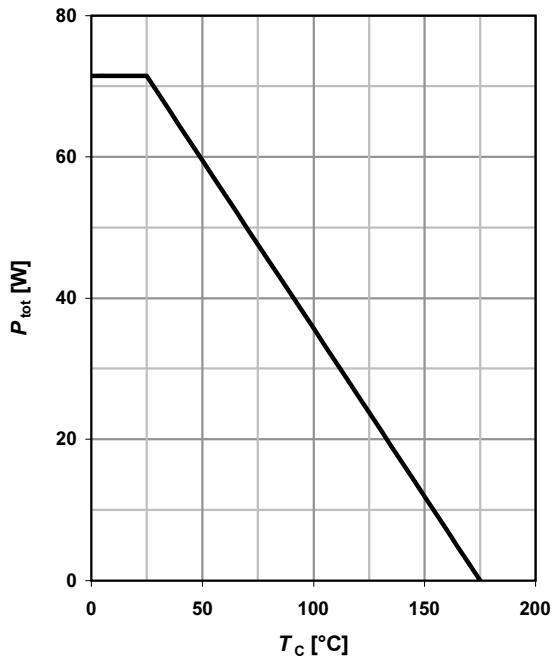
**Reverse Diode**

Diode continuous forward current	$I_s$	$T_c=25 \text{ }^\circ\text{C}$	-	-	43	A
Diode pulse current	$I_{s,pulse}$		-	-	172	
Diode forward voltage	$V_{SD}$	$V_{GS}=0 \text{ V}, I_F=33 \text{ A}, T_j=25 \text{ }^\circ\text{C}$	-	1	1.2	V
Reverse recovery time	$t_{rr}$	$V_R=15 \text{ V}, I_F=33 \text{ A}, di_F/dt=100 \text{ A}/\mu\text{s}$	-	55	-	ns
Reverse recovery charge	$Q_{rr}$		-	92	-	nC

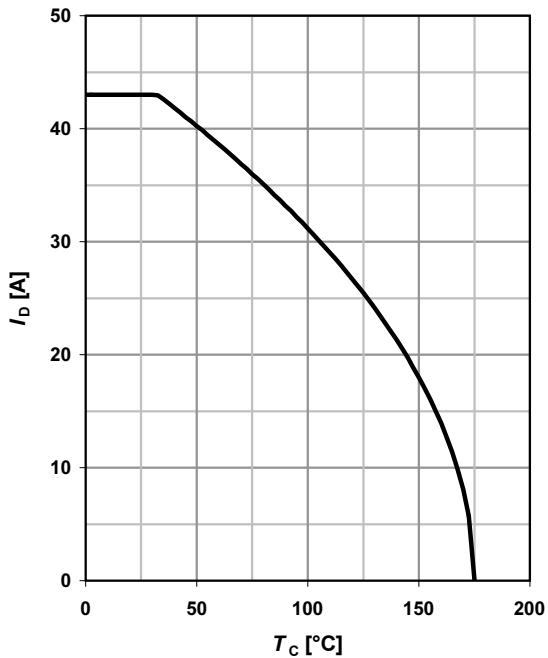
<sup>6)</sup> See figure 16 for gate charge parameter definition

**1 Power dissipation**

$$P_{\text{tot}} = f(T_c)$$

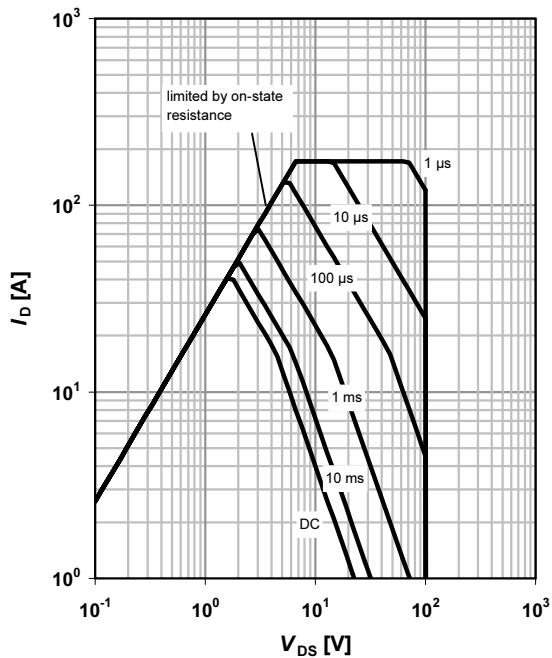

**2 Drain current**

$$I_D = f(T_c); V_{GS} \geq 10 \text{ V}$$


**3 Safe operating area**

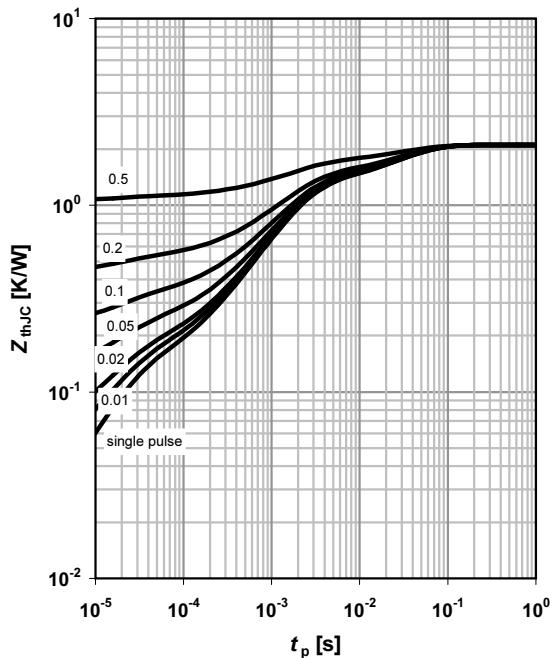
$$I_D = f(V_{DS}); T_c = 25 \text{ °C}; D = 0$$

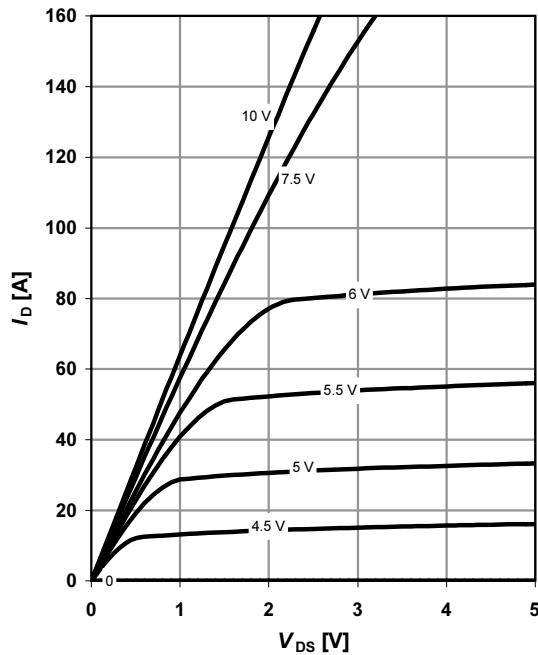
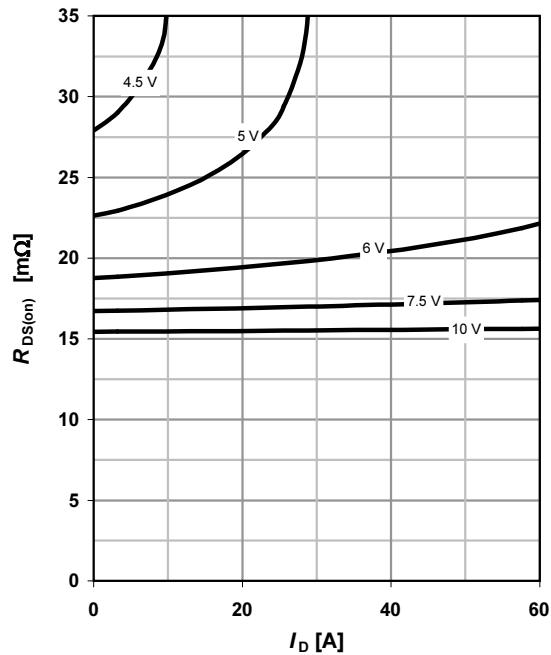
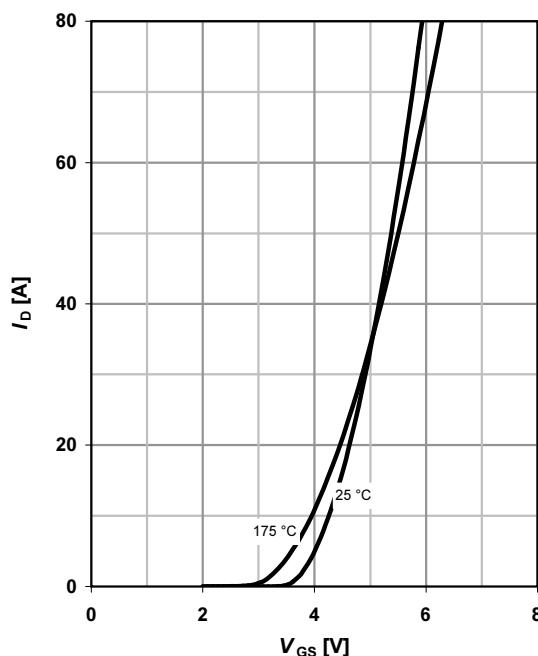
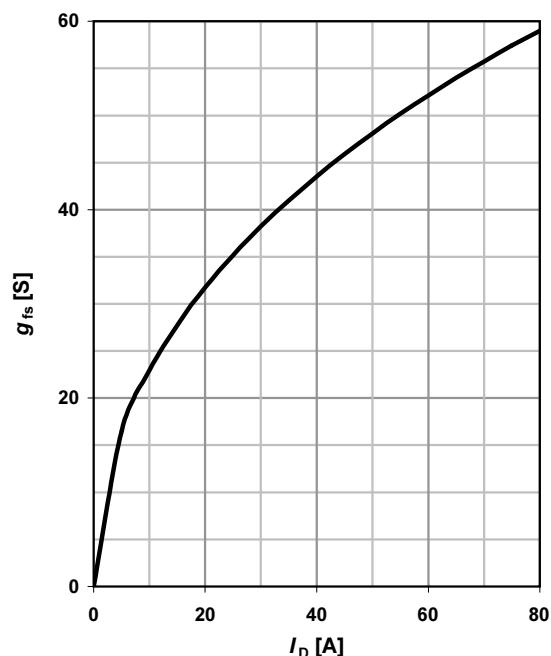
parameter:  $t_p$

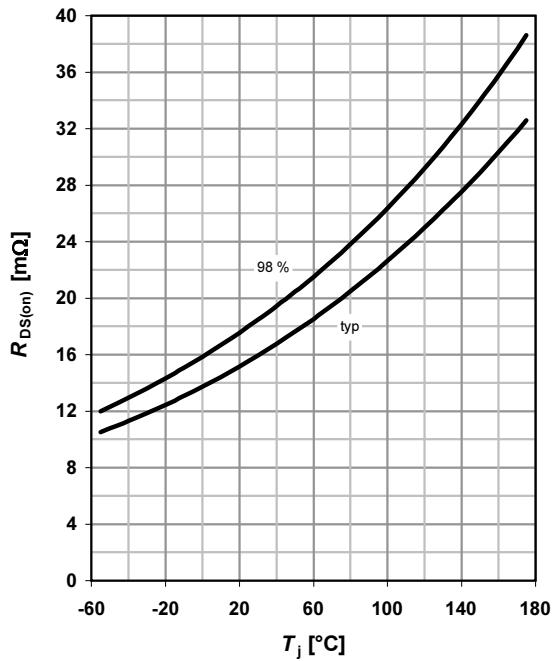

**4 Max. transient thermal impedance**

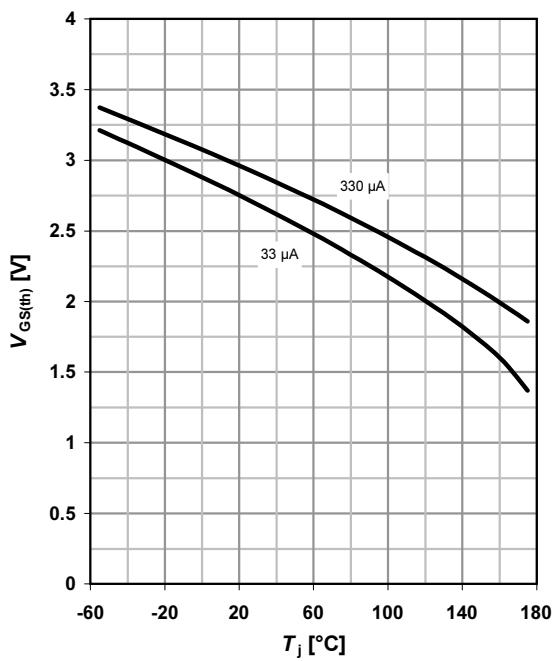
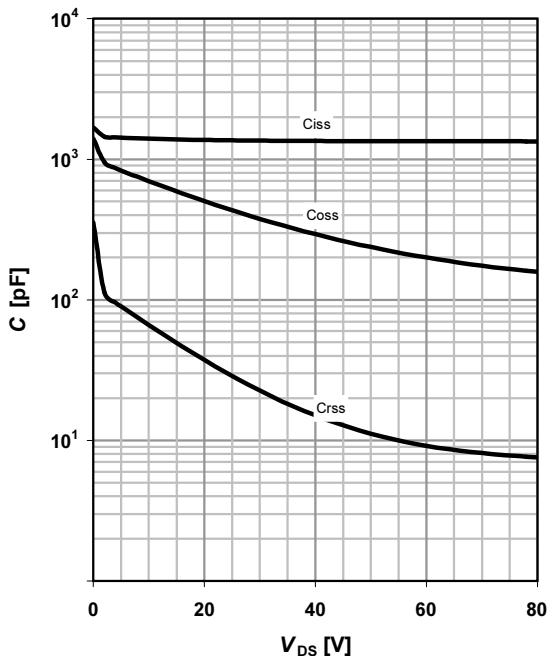
$$Z_{\text{thJC}} = f(t_p)$$

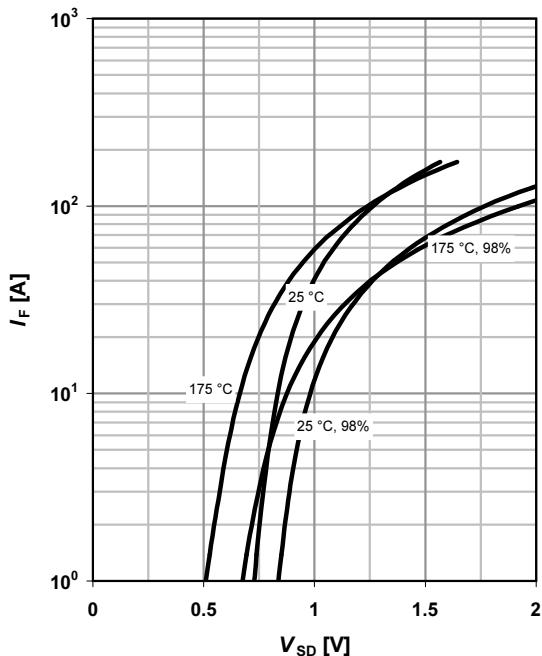
parameter:  $D = t_p/T$



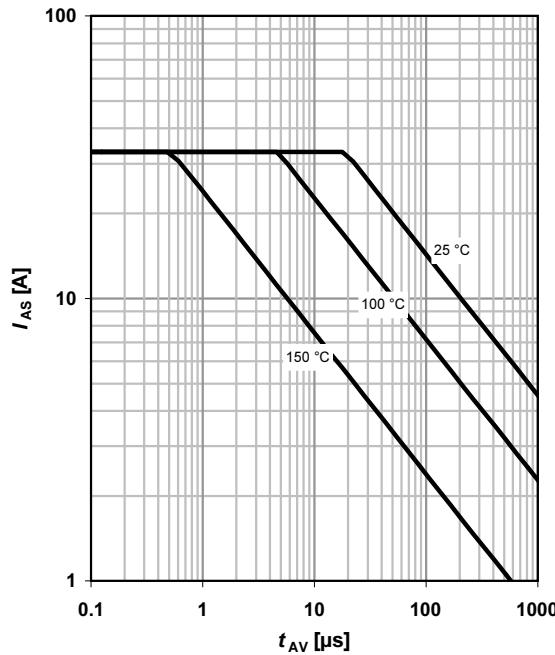
**5 Typ. output characteristics**
 $I_D = f(V_{DS})$ ;  $T_j = 25^\circ\text{C}$ 
parameter:  $V_{GS}$ 
**6 Typ. drain-source on resistance**
 $R_{DS(on)} = f(I_D)$ ;  $T_j = 25^\circ\text{C}$ 
parameter:  $V_{GS}$ 
**7 Typ. transfer characteristics**
 $I_D = f(V_{GS})$ ;  $|V_{DS}| > 2|I_D|R_{DS(on)max}$ 
parameter:  $T_j$ 
**8 Typ. forward transconductance**
 $g_{fs} = f(I_D)$ ;  $T_j = 25^\circ\text{C}$ 


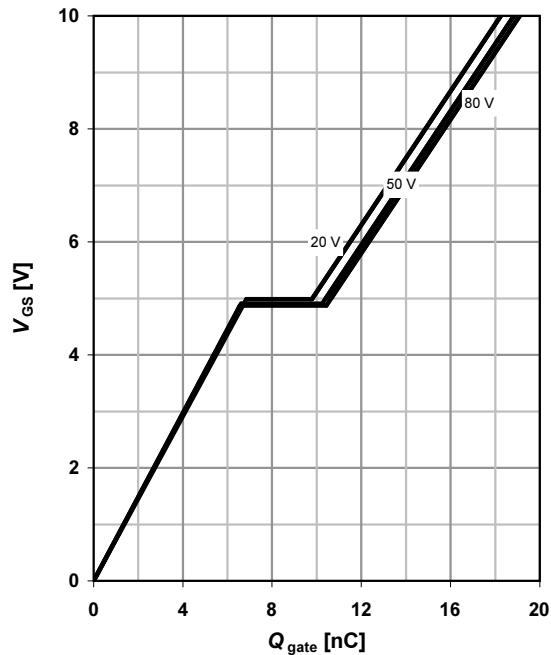
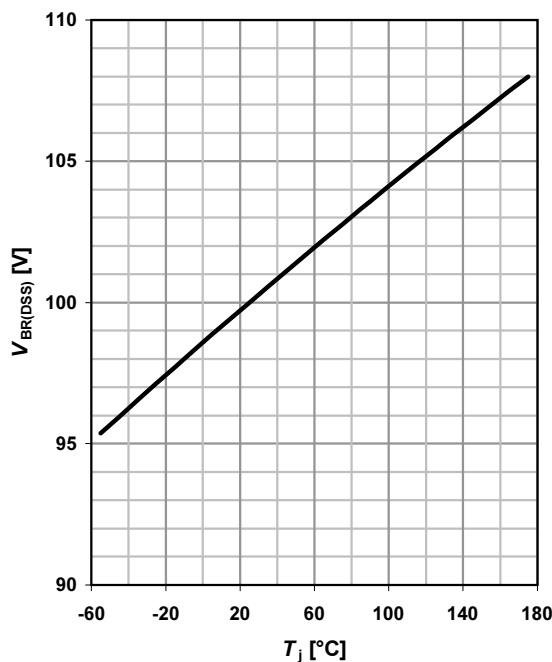
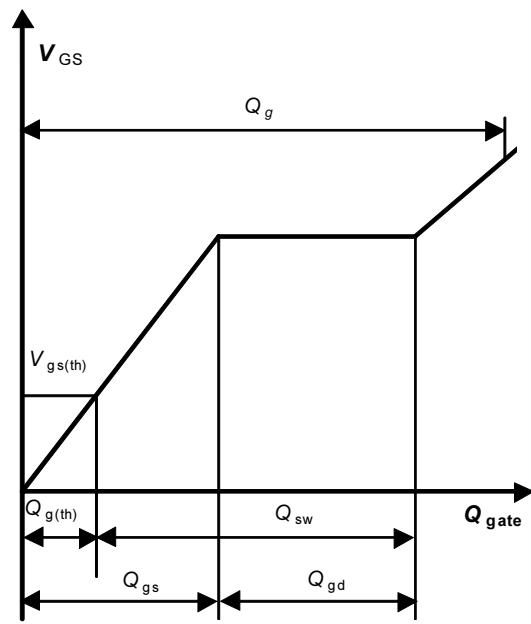
**9 Drain-source on-state resistance**
 $R_{DS(on)} = f(T_j); I_D = 33 \text{ A}; V_{GS} = 10 \text{ V}$ 

**10 Typ. gate threshold voltage**
 $V_{GS(th)} = f(T_j); V_{GS} = V_{DS}$ 

 parameter:  $I_D$ 

**11 Typ. capacitances**
 $C = f(V_{DS}); V_{GS} = 0 \text{ V}; f = 1 \text{ MHz}$ 

**12 Forward characteristics of reverse diode**
 $I_F = f(V_{SD})$ 

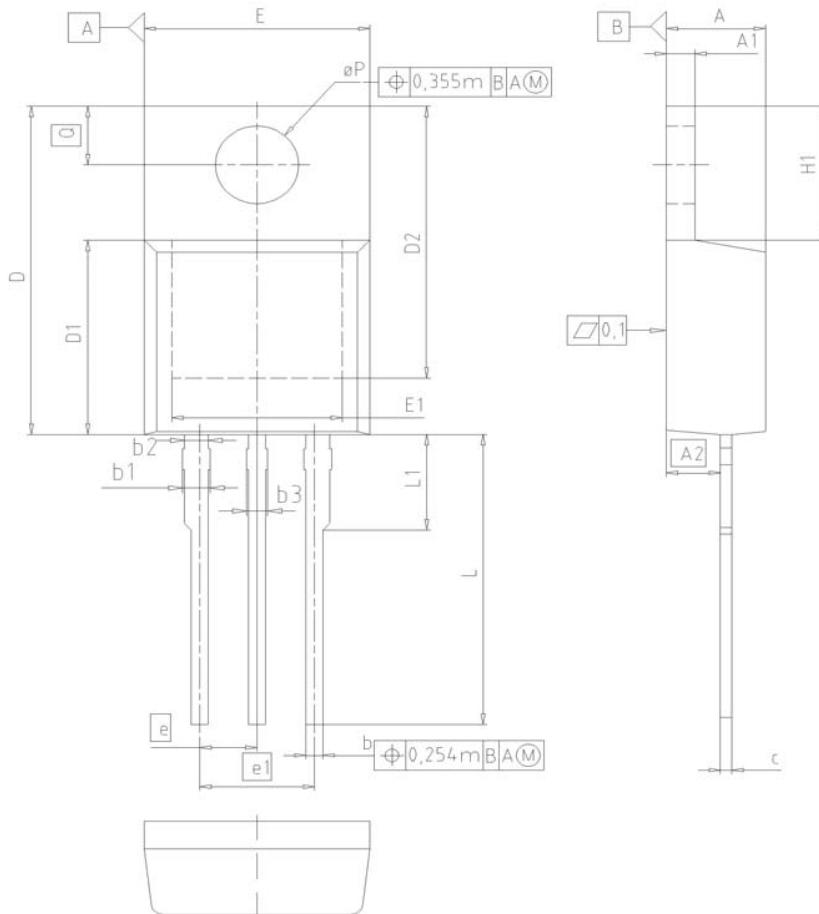
 parameter:  $T_j$ 


**13 Avalanche characteristics**
 $I_{AS} = f(t_{AV})$ ;  $R_{GS} = 25 \Omega$ 

parameter:  $T_{j(start)}$ 

**14 Typ. gate charge**
 $V_{GS} = f(Q_{gate})$ ;  $I_D = 33 \text{ A pulsed}$ 

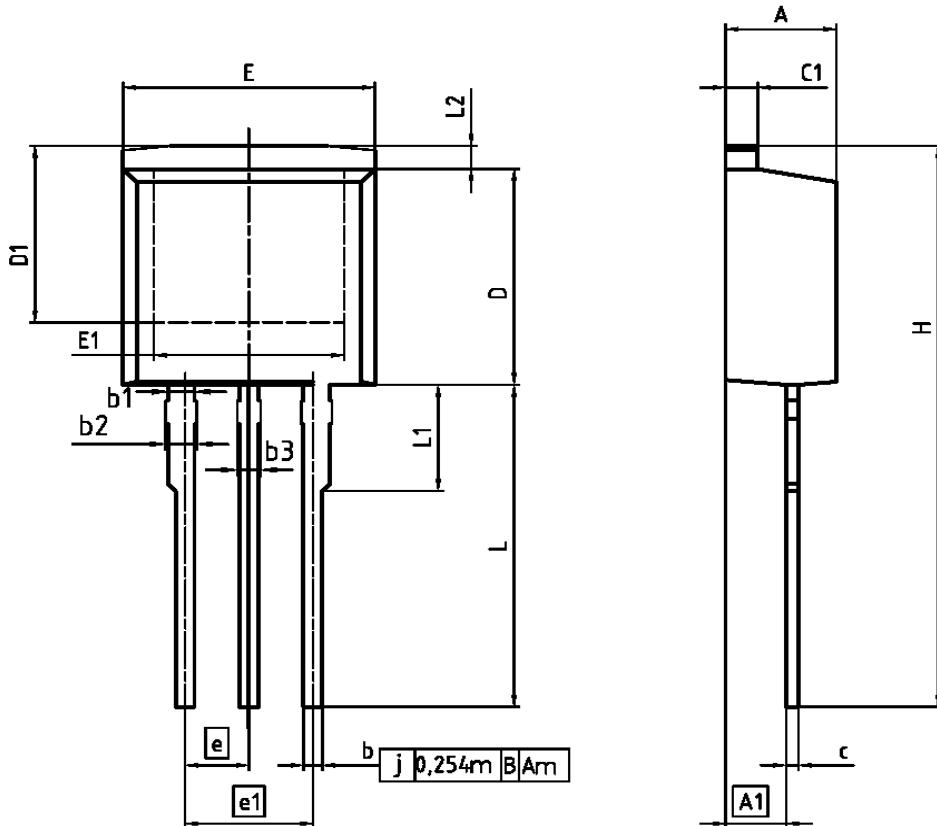
parameter:  $V_{DD}$ 

**15 Drain-source breakdown voltage**
 $V_{BR(DSS)} = f(T_j)$ ;  $I_D = 1 \text{ mA}$ 

**16 Gate charge waveforms**


**PG-T0-220**



DIM	MILLIMETERS		INCHES	
	MIN	MAX	MIN	MAX
A	4.30	4.57	0.169	0.180
A1	1.17	1.40	0.046	0.055
A2	2.15	2.72	0.085	0.107
b	0.65	0.86	0.026	0.034
b1	0.95	1.40	0.037	0.055
b2	0.95	1.15	0.037	0.045
b3	0.65	1.15	0.026	0.045
c	0.33	0.60	0.013	0.024
D	14.81	15.95	0.583	0.628
D1	8.51	9.45	0.335	0.372
D2	12.19	13.10	0.480	0.516
E	9.70	10.36	0.382	0.408
E1	6.50	8.60	0.256	0.339
e	2.54		0.100	
e1	5.08		0.200	
N	3		3	
H1	5.90	6.90	0.232	0.272
L	13.00	14.00	0.512	0.551
L1	-	4.80	-	0.189
øP	3.60	3.89	0.142	0.153
Q	2.60	3.00	0.102	0.118

DOCUMENT NO.
Z8B00003318
SCALE
0 2.5 0 2.5 5mm
EUROPEAN PROJECTION
ISSUE DATE
23-08-2007
REVISION
05



DIM	MILLIMETERS		INCHES	
	MIN	MAX	MIN	MAX
A	4.300	4.572	0.169	0.180
A1	2.150	2.718	0.085	0.107
b	0.650	0.864	0.026	0.034
b1	0.950	1.093	0.037	0.043
b2	0.950	1.400	0.037	0.055
b3	0.650	1.118	0.026	0.044
c	0.330	0.600	0.013	0.024
c1	1.170	1.400	0.046	0.055
D	8.509	8.450	0.335	0.372
D1	6.900	-	0.272	-
E	9.700	10.363	0.382	0.408
E1	6.500	8.600	0.256	0.339
e	2.540		0.100	
e1	5.080		0.200	
N	3		3	
L	13.000	14.000	0.512	0.551
L1	-	4.800	-	0.189
L2	-	1.727	-	0.068

REFERENCE JEDEC TO262
SCALE 0 2.5 0 2.5 5mm
EUROPEAN PROJECTION
ISSUE DATE 05-05-2006
FILE TO262_1

**Published by**

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81726 Munich, Germany  
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